# PH4330L

# N-channel TrenchMOS logic level FET

Rev. 01 — 22 October 2008

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

### 1.2 Features and benefits

- 100 % gate resistance tested
- 100 % ruggedness tested
- Lead-free package
- Logic level threshold

- Optimized for use in DC-DC converters
- Very low switching and conduction losses

### 1.3 Applications

- DC-to-DC convertors
- PC motherboards

- Switched-mode power supplies
- Voltage regulators

#### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	30	V
I <sub>D</sub>	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	95.9	Α
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure 11}}{\text{Figure 12}};$	-	5.4	-	nC
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \underline{\text{Figure 9}}; \text{ see}$ $\underline{\text{Figure 10}}$	-	3.6	4.3	mΩ



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### **Pinning information**

**Pinning information** Table 2.

	_			
Pin	Symbol	Description	Simplified outline	Graphic symbol
1, 2, 3	S	source		
4	G	gate	mb	D
mb	D	mounting base; connected to drain	Q	mbb076 S
			SOT669 (LFPAK)	

#### **Ordering information** 3.

Table 3. **Ordering information** 

Type number	Package		
	Name	Description	Version
PH4330L	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

# **Limiting values**

Limiting values Table 4.

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	30	V
$V_{DGR}$	drain-gate voltage	25 °C ≤ $T_j$ ≤ 150 °C; $R_{GS}$ = 20 kΩ	-	30	V
$V_{GS}$	gate-source voltage		-20	20	V
$I_D$	drain current	$V_{GS} = 10 \text{ V}$ ; $T_{mb} = 25 \text{ °C}$ ; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	95.9	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{}$	-	60.1	А
I <sub>DM</sub>	peak drain current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$ ; see Figure 3	-	240	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	62.5	W
T <sub>stg</sub>	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25  ^{\circ}C$	-	52	Α
I <sub>SM</sub>	peak source current	$t_p$ = 10 $\mu$ s; pulsed; $T_{mb}$ = 25 °C	-	208	Α
Avalanche	ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 49 A; $V_{sup}$ ≤ 25 V; $t_p$ = 0.12 ms; $R_{GS}$ = 50 Ω; unclamped inductive load	-	121	mJ

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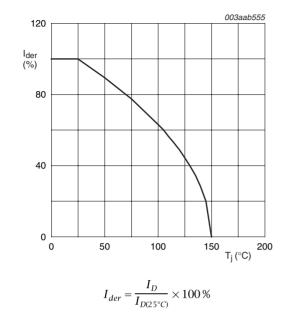


Fig 1. Normalized continuous drain current as a function of solder point temperature

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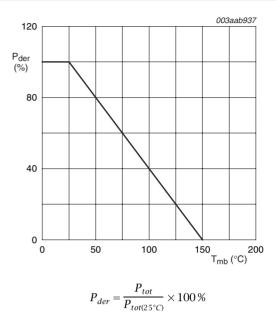


Fig 2. Normalized total power dissipation as a function of solder point temperature

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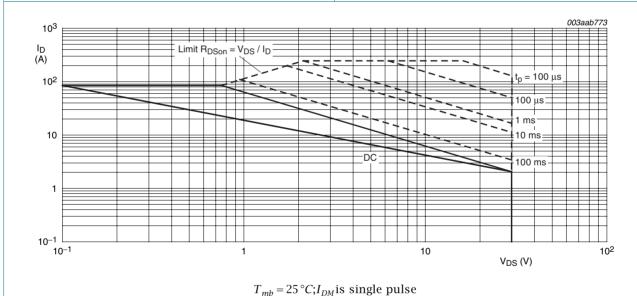


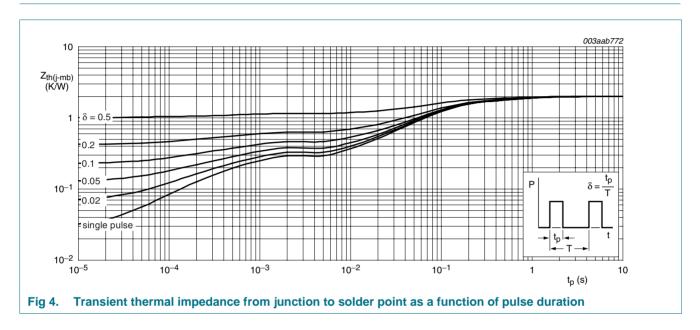
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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# 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
breakdown voltage		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
V <sub>GS(th)</sub> gate-source threshold voltage		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see Figure 7; see Figure 8	1.3	1.7	2.5	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see Figure 7; see Figure 8	-	-	2.6	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 150$ °C; see Figure 7; see Figure 8	8.0	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}; \text{ see}$ Figure 9; see Figure 10	-	3.6	4.3	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 150 \text{ °C}; \text{ see}$ Figure 9; see Figure 10	-	6	6.8	mΩ
_		$V_{GS} = 4.5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; see Figure 9; see Figure 10	-	5.6	7	mΩ
$R_G$	gate resistance	f = 1 MHz	-	0.51	-	Ω
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ; see	-	22.9	-	nC
$Q_{GS}$	gate-source charge	Figure 11; see Figure 12	-	9	-	nC
Q <sub>GS1</sub>	pre-threshold gate-source charge		-	5.5	-	nC
Q <sub>GS2</sub>	post-threshold gate-source charge		-	3.5	-	nC
Q <sub>GD</sub>	gate-drain charge		-	5.4	-	nC
V <sub>GS(pI)</sub>	gate-source plateau voltage	$I_D = 25 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	2.8	-	V
C <sub>iss</sub>	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 13}{\text{ Figure } 13}$	-	2786	-	pF
		$V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 13}{\text{Figure } 13}$	-	3300	-	pF
C <sub>oss</sub>	output capacitance	V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 0 V; f = 1 MHz;	-	579	-	pF
C <sub>rss</sub>	reverse transfer capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	297	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	28	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5.6 \Omega$	-	43	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	35	-	ns
t <sub>f</sub>	fall time		-	19	-	ns

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Characteristics ... continued Table 6.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 14	-	0.85	-	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	47	-	ns
$Q_r$	recovered charge	$V_{DS} = 30 \text{ V}$	-	17	-	nC

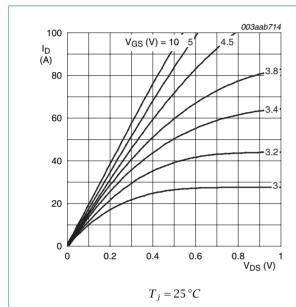
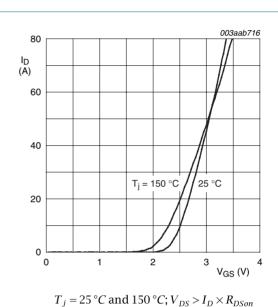


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



Transfer characteristics: drain current as a Fig 6. function of gate-source voltage; typical values

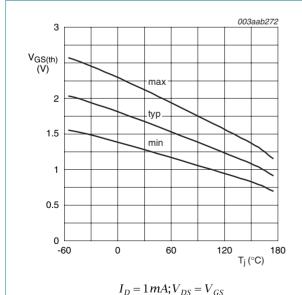


Fig 7. Gate-source threshold voltage as a function of junction temperature

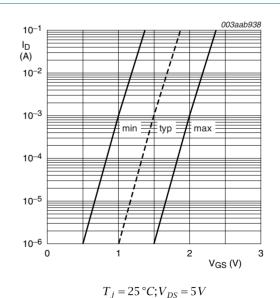


Fig 8. Sub-threshold drain current as a function of gate-source voltage

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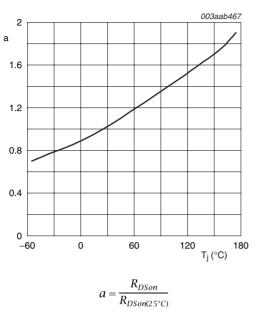


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature

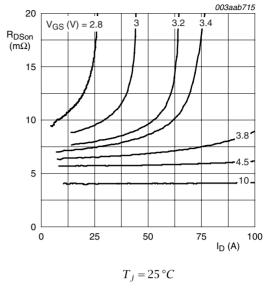


Fig 10. Drain-source on-state resistance as a function of drain current; typical values

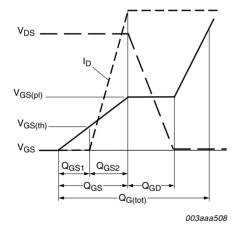
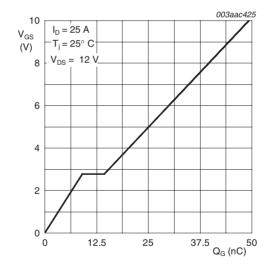


Fig 11. Gate charge waveform definitions



 $I_D = 25A; V_{DS} = 12V$ 

Fig 12. Gate-source voltage as a function of gate charge; typical values

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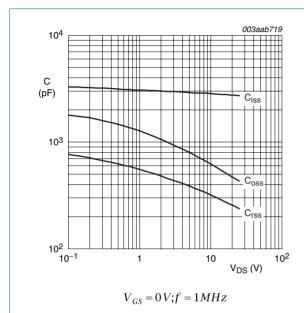
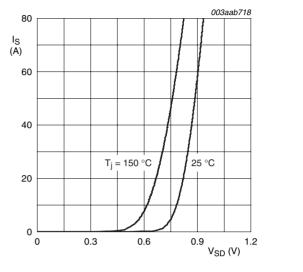


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $T_i = 25 \,^{\circ}C$  and  $150 \,^{\circ}C$ ;  $V_{GS} = 0 \, V$ 

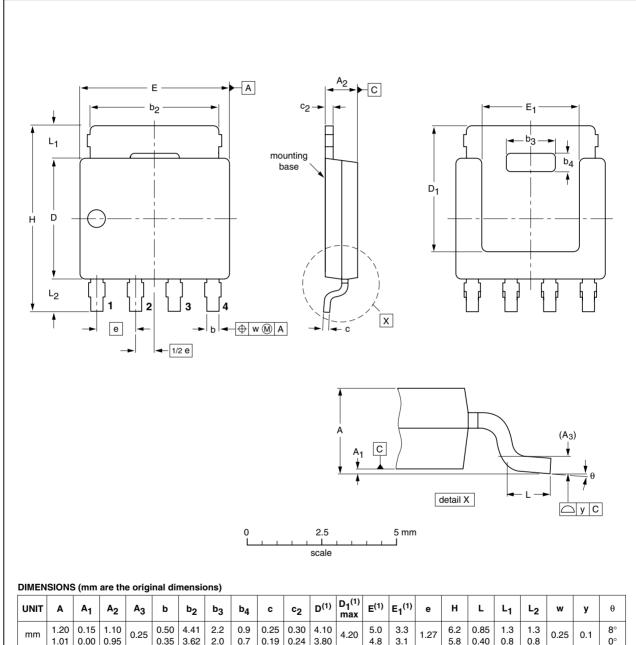
Fig 14. Source current as a function of source-drain voltage; typical values

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### Package outline

### Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



UNIT	A	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b	b <sub>2</sub>	b <sub>3</sub>	b <sub>4</sub>	С	c <sub>2</sub>	D <sup>(1)</sup>	D <sub>1</sub> <sup>(1)</sup> max	E <sup>(1)</sup>	E <sub>1</sub> <sup>(1)</sup>	е	Н	L	L <sub>1</sub>	L <sub>2</sub>	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	0.30 0.24	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT669		MO-235			<del>04-10-13</del> 06-03-16

Fig 15. Package outline SOT669 (LFPAK)

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### N-channel TrenchMOS logic level FET

### 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH4330L_1	20081022	Product data sheet	-	-

#### N-channel TrenchMOS logic level FET

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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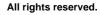
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